RELIABILITY MONITOR

DS1232L APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DE045054ABB	8	SOIC	150x1.4	OSEP

PROCESS 1P, 1M, 0.8um, PdplDiode, Low Vts , Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26864	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.26E+07		0
26861	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26862	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		238	168	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
26863	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
26865	TEMP CYCLE	-55C TO 125C		40	300	CYCL	1
				39	1000	CYCL	0
		TOTAL:					1

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
OPENS	FAILED ALL TESTS		

26866	HAST	130C, 85%R.H.,5.5V		77	88	HOUR	0
		TOTAL:					0

PROJECT NO: 17981

RELIABILITY MONITOR

DS1232L APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DE045054ABB	8	SOIC	150x1.4	OSEP

PROCESS 1P, 1M, 0.8um, PdplDiode, Low Vts , Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 0

Tuse: 25 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26867	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 17981

RELIABILITY MONITOR

DS1232L JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DK046225ABB	8	SOIC	150x1.4	ATP (Amkor, PI)

PROCESS 1P, 1M, 0.8um, PdplDiode, Low Vts , Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27339	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		80	336	HOUR	0
		125C, 7.0 VOLTS		80	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.55E+07		0
27336	ULTRASOUND	J-STD-020		4			
		TOTAL:					
27337	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		241	168	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	0
		TOTAL:					0
27338	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27340	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
27341	HAST	130C, 85%R.H.,5.5V		77	100	HOUR	1
		TOTAL:					1

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
LEVELS TEST	RESET		

PROJECT NO: 18776

RELIABILITY MONITOR

DS1232L JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DK046225ABB	8	SOIC	150x1.4	ATP (Amkor, PI)

PROCESS 1P, 1M, 0.8um, PdplDiode, Low Vts , Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27342	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18776

RELIABILITY MONITOR

DS1233Z-10 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0101	DA048537AF	3	SOT223	140x1.7	Fastech

PROCESS 1P, 1M, 1.2um, ZTC P1, Ndepletion ,L Passivation w/Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26871	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.26E+07		0
26868	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26869	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		238	168	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
26872	TEMP CYCLE	-55C TO 125C		40	700	CYCL	10
				29	1000	CYCL	0
		TOTAL:					10

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
ICC STANDBY	#1 MIXED; #2-11 ICC STANDBY		

26873	HAST	130C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
26874	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

PROJECT NO: 17982

RELIABILITY MONITOR

DS1233Z-10 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0101	DA048537AF	3	SOT223	140x1.7	Fastech

PROCESS 1P, 1M, 1.2um, ZTC P1, Ndepletion ,L Passivation w/Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 0

Tuse: 25 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS

PROJECT NO: 17982

RELIABILITY MONITOR

DS1233Z-10 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0110	DM048543AA	3	SOT223	140x1.7	Carsem

PROCESS 1P, 1M, 1.2um, ZTC P1, Ndepletion ,L Passivation w/Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27352	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		68	336	HOUR	0
		TOTAL:	FAIL RATE (Fits):	43	DEVICE HRS: 2.15E+07		0
27349	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27350	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		241	168	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	0
		TOTAL:					0
27353	TEMP CYCLE	-55C TO 125C		40	700	CYCL	0
				26	1000	CYCL	0
		TOTAL:					0
27354	HAST	130C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
27355	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

PROJECT NO: 18777

RELIABILITY MONITOR

DS1233Z-10 OCT '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0128	DA102602AC	3	SOT223	140x1.7	Fastech

PROCESS 1P, 1M, 1.2um, ZTC P1, Ndepletion ,L Passivation w/Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
28006	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		68	336	HOUR	0
		TOTAL:	FAIL RATE (Fits):	43	DEVICE HRS: 2.15E+07		0
28003	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
28004	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		241	168	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	1
		TOTAL:					1

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
CONTINUITY	#1 CONTINUITY		

28007	TEMP CYCLE	-55C TO 125C		40	700	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
28008	HAST	130C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
28009	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

PROJECT NO: 19603

RELIABILITY MONITOR

DS1267-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0104	DK043419AAB	20	TSSOP	4.4x0.9	ATP (Amkor, PI)

PROCESS 1P, 1M, 1.2um, II Poly1 , TEOS Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26979	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V		75	336	HOUR	0
		125C, 6.0 V, -4.0V		75	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 6.95E+07		0
26976	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26977	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		238	168	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
26978	PRECONDITION U/S	J-STD-020		4			
		TOTAL:					
26980	TEMP CYCLE	-55C TO 125C		35	300	CYCL	0
				35	1000	CYCL	0
		TOTAL:					0
26981	BIASED MOISTURE	85/85, 5.5 VOLTS		75	274	HOUR	0
				75	959	HOUR	0
		TOTAL:					0

PROJECT NO: 18202

RELIABILITY MONITOR

DS1267-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0104	DK043419AAB	20	TSSOP	4.4x0.9	ATP (Amkor, PI)

PROCESS 1P, 1M, 1.2um, II Poly1 , TEOS Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26982	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	34	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18202

RELIABILITY MONITOR

DS1620 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0106	DH045040AAG	8	SOIC	208x1.9	CPS (ChipPac, China

PROCESS 1P, 1M, 0.8um, E2PROM, DSD w/LV Wel Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26776	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
		TOTAL: FAIL RATE (Fits): #Div/0!	DEVICE HRS: 0.00E+00			0
26773	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26774	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
26775	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26780	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0
		TOTAL:				0
26781	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0

PROJECT NO: 17781

RELIABILITY MONITOR

DS1620 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0109	DH046190AAI	8	SOIC	208x1.9	CPS (ChipPac, China
PROCESS	1P, 1M, 0.8um, E2PROM, DSD w/LV Wel				Passivation w/Nov TEOS Oxide-Nitride		

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27093	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.26E+07		0
27090	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27091	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		241	168	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	0
		TOTAL:					0
27092	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27094	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
27095	BIASED MOISTURE	85/85, 5.5 VOLTS		70	274	HOUR	1
				69	959	HOUR	0

PROJECT NO: 18427

RELIABILITY MONITOR

DS1620 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0109	DH046190AAI	8	SOIC	208x1.9	CPS (ChipPac, China

PROCESS 1P, 1M, 0.8um, E2PROM, DSD w/LV Wel Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				1
FAILURE MODE	**VERIFICATION**	**FA NUMBER**	**FAILURE MECHANISM**			
OPENS	CONTINUITY PIN 8					
27096	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0
		TOTAL:				0
27097	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0

PROJECT NO: 18427

RELIABILITY MONITOR

DS1620 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0111	DJ051232AAI	8	SOIC	208x1.9	NSEB

PROCESS 1P, 1M, 0.8um, E2PROM, DSD w/LV Wel Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27859	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		80	336	HOUR	0
		125C, 7.0 VOLTS		80	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.55E+07		0
27856	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27857	STORAGE LIFE	125C		244	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		244	168	HOUR	
	CONVECTION REFLOW	235C		244	3	PASS	0
		TOTAL:					0
27858	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27860	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
27861	BIASED MOISTURE	85/85, 5.5 VOLTS		70	274	HOUR	0
				70	959	HOUR	0
		TOTAL:					0

PROJECT NO: 19202

RELIABILITY MONITOR

DS1620 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0111	DJ051232AAI	8	SOIC	208x1.9	NSEB

PROCESS 1P, 1M, 0.8um, E2PROM, DSD w/LV Wel Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27862	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0
		TOTAL:				0
27863	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0

PROJECT NO: 19202

RELIABILITY MONITOR

DS1620 DEC '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0112	DH052443AAD	8	SOIC	208x1.9	CPS (ChipPac, China

PROCESS 1P, 1M, 0.8um, E2PROM, DSD w/LV Wel Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
28593	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		80	336	HOUR	0
		125C, 7.0 VOLTS		80	1000	HOUR	
		TOTAL:	FAIL RATE (Fits):	36	DEVICE HRS: 2.54E+07		0
28591	STORAGE LIFE	125C		244	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		244	168	HOUR	
	CONVECTION REFLOW	235C		244	3	PASS	0
		TOTAL:					0
28594	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
28595	BIASED MOISTURE	85/85, 5.5 VOLTS		70	274	HOUR	0
		TOTAL:					0
28596	WRITE CYCLE STRESS	85 C, 7.0 VOLTS		50	50	KCYC	0
		TOTAL:					0
28597	STORAGE LIFE	150C		50	336	HOUR	0
		TOTAL:					0

PROJECT NO: 20886

RELIABILITY MONITOR

DS1803-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0105	DE047362AAB	16	SOIC	150x1.4	OSEP

PROCESS 1P, 2M, 0.8um, PdplDiode , WJ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26609	INFANT LIFE	125C, 7.0 VOLTS		232	48	HOUR	0
26610	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	11	DEVICE HRS: 8.21E+07		0
26606	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26607	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		238	168	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
26608	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
26611	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				34	1000	CYCL	0
		TOTAL:					0
26612	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				66	959	HOUR	3

PROJECT NO: 17281

RELIABILITY MONITOR

DS1803-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0105	DE047362AAB	16	SOIC	150x1.4	OSEP

PROCESS 1P, 2M, 0.8um, PdplDiode, Ti/TiN M1+M2 Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 0

Tuse: 25 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				3
FAILURE MODE	**VERIFICATION**	**FA NUMBER**	**FAILURE MECHANISM**			
LO						
26613	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	30	96	HOUR	0
		TOTAL:				0

PROJECT NO: 17281

RELIABILITY MONITOR

DS1803-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0115	DM052456ACB	16	SOIC	150x1.4	Carsem

PROCESS 1P, 2M, 0.8um, PdplDiode , WJ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26993	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		76	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 6.92E+07		0
26990	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26991	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		238	168	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
26994	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				31	1000	CYCL	0
		TOTAL:					0
26995	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
26996	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		37	96	HOUR	0
		TOTAL:					0

PROJECT NO: 18204

RELIABILITY MONITOR

DS1803-010 AUG '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0119	DE105519ACA	16	SOIC	150x1.4	OSEP

PROCESS 1P, 2M, 0.8um, PdplDiode, Ti/TiN M1+M2 Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27563	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		80	336	HOUR	0
		125C, 7.0 VOLTS		80	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.55E+07		0
27560	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27561	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		241	168	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	0
		TOTAL:					0
27564	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
27565	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
27566	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

PROJECT NO: 18889

RELIABILITY MONITOR

DS2108 AUG '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0029	DK016058AAG	24	SOIC	300x2.3	ATP (Amkor, PI)

PROCESS 1P,1M,5.0um,NegZTC P1R,30VNF&PF,U Laser/Nit - Pass/Nit - General LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
25857	INFANT LIFE	125C, 6.0 VOLTS		231	48	HOUR	0
25858	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		77	336	HOUR	0
		125C, 6.0 VOLTS		76	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	11	DEVICE HRS: 8.13E+07		0
25854	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
25855	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.		238	144	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
25856	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
25859	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
25860	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	3
				74	959	HOUR	0

PROJECT NO: 16238

RELIABILITY MONITOR

DS2108 AUG '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0029	DK016058AAG	24	SOIC	300x2.3	ATP (Amkor, PI)

PROCESS 1P,1M,5.0um,NegZTC P1R,30VNF&PF,U Laser/Nit - Pass/Nit - General LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				3

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
FUSE	UNKNOWN - NO FURTHER ANALYSIS		

25861	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	33	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16238

RELIABILITY MONITOR

DS2118M SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0124	DM106644AAB	36	SSOP	7.5x2.4	Carsem

PROCESS 1P, 1M, 0.6um,ALOCOS,NZTC P1R,Pdpl Laser/Nit - Pass/Nit - General LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27874	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		80	336	HOUR	0
		125C, 6.0 VOLTS		70	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	14	DEVICE HRS: 6.60E+07		0
27871	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27872	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		241	168	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	1
		TOTAL:					1
FAILURE MODE	**VERIFICATION**		**FA NUMBER**	**FAILURE MECHANISM**			
V_DIFFSENS LVD	V DIFFSENS LVD						
27873	PRECONDITION U/S	J-STD-020		4			4
		TOTAL:					4
FAILURE MODE	**VERIFICATION**		**FA NUMBER**	**FAILURE MECHANISM**			
US	DIE SURFACE DELAMINATION						
27875	TEMP CYCLE	-55C TO 125C		80	300	CYCL	0
				70	1000	CYCL	0
		TOTAL:					0
27876	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		76	96	HOUR	0

PROJECT NO: 19204

RELIABILITY MONITOR

DS2118M SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0124	DM106644AAB	36	SSOP	7.5x2.4	Carsem

PROCESS 1P, 1M, 0.6um,ALOCOS,NZTC P1R,Pdpl Laser/Nit - Pass/Nit - General LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 0

Tuse: 25 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0

PROJECT NO: 19204

RELIABILITY MONITOR

DS21352 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATP (Amkor, PI)

PROCESS 2P, 2M, 0.6um, P2Cap, PdD, HP Vts, GO Laser/TEOS Ox - Pass/Nit - Gen.LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27346	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		77	336	HOUR	0
		125C, 6.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.14E+07		0
27343	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27344	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.		238	40	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	5
		TOTAL:					5

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
BIN 3	#7: DSOM		
BIN 2	#2&5: JITTER TOLERANCE		
BIN 4	#6&9: PLS		

27345	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27347	TEMP CYCLE	-55C TO 125C		80	300	CYCL	0
				79	1000	CYCL	0
		TOTAL:					0
27348	HAST, NO BIAS	130C, 85% R.H.		62	200	HOUR	0

PROJECT NO: 18661

RELIABILITY MONITOR

DS21352 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATP (Amkor, PI)

PROCESS 2P, 2M, 0.6um, P2Cap, PdD, HP Vts, GO Laser/TEOS Ox - Pass/Nit - Gen.LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	25 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	0		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0

PROJECT NO: 18661

RELIABILITY MONITOR

DS2154 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0107	DC040702AA-1	100	LQFP	14x14x	Stats

PROCESS 2P, 2M, 0.8um, Nd Cap, P2 Cap , N+ESD Laser/TEOS Ox - Pass/Nit - Gen.LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27101	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		77	336	HOUR	0
		125C, 6.0 VOLTS		76	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.11E+07		0
27098	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27099	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.		238	40	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
27100	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27102	TEMP CYCLE	-55C TO 125C		80	300	CYCL	0
				80	1000	CYCL	0
		TOTAL:					0
27103	HAST, NO BIAS	130C, 85% R.H.		76	200	HOUR	0
		TOTAL:					0

PROJECT NO: 18642

RELIABILITY MONITOR

DS2154 SEP '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0125	DN104641AA-1	100	LQFP	14x14x	ATK (Amkor, K)

PROCESS 2P, 2M, 0.8um, Nd Cap, P2 Cap , N+ESD Laser/TEOS Ox - Pass/Nit - Gen.LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27841	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		80	336	HOUR	0
		125C, 6.0 VOLTS		80	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.55E+07		0
27838	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27839	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.		241	40	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	0
		TOTAL:					0
27840	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27842	TEMP CYCLE	-55C TO 125C		80	300	CYCL	0
				80	1000	CYCL	0
		TOTAL:					0
27843	HAST, NO BIAS	130C, 85% R.H.		77	200	HOUR	0
		TOTAL:					0

PROJECT NO: 19201

RELIABILITY MONITOR

DS2154 DEC '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0126	DK119150AAA	100	LQFP	14x14x	ATP (Amkor, PI)

PROCESS 2P, 2M, 0.8um, Nd Cap, P2 Cap , N+ESD Laser/TEOS Ox - Pass/Nit - Gen.LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
28583	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		80	336	HOUR	0
		TOTAL:	FAIL RATE (Fits):	36	DEVICE HRS: 2.54E+07		0
28580	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
28581	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.		238	192	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	1
		TOTAL:					1
FAILURE MODE	**VERIFICATION**		**FA NUMBER**	**FAILURE MECHANISM**			
CONTINUITY	CONTINUITY						
28582	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
28584	TEMP CYCLE	-55C TO 125C		72	300	CYCL	0
		TOTAL:					0
28585	HAST, NO BIAS	130C, 85% R.H.		72	200	HOUR	0
		TOTAL:					0

PROJECT NO: 20885

RELIABILITY MONITOR

DS2175 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0050	DK036683ABD	16	SOIC	300x2.3	ATP (Amkor, PI)
PROCESS	1P, 1M, 2.0um, Pfield		, WJ BP	Passivation w/Nitride			

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26883	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.26E+07		0
26880	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26881	TEMP CYCLE	-55C TO 125C		238	10	CYCL	
	STORAGE LIFE	125C		238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.		238	168	HOUR	
	CONVECTION REFLOW	235C		238	3	PASS	0
		TOTAL:					0
26882	PRECONDITION U/S	J-STD-020		4			
		TOTAL:					
26884	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
26885	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
		TOTAL:					0

PROJECT NO: 18002

RELIABILITY MONITOR

DS2175 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0050	DK036683ABD	16	SOIC	300x2.3	ATP (Amkor, PI)

PROCESS 1P, 1M, 2.0um, Pfield , WJ BP Passivation w/Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C

Ea: 0.7 Vuse: 5.5 Volts

β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26886	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18002

RELIABILITY MONITOR

DS21Q43A SEP '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0047	DC036714AAD	128	LQFP	14x20x	Stats

PROCESS 1P, 1M, 0.6um, Pdepletion, Low Vts , Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27880	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		70	336	HOUR	0
		TOTAL:	FAIL RATE (Fits):	41	DEVICE HRS: 2.22E+07		0
27877	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27878	STORAGE LIFE	125C		241	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.		241	40	HOUR	
	CONVECTION REFLOW	235C		241	3	PASS	0
		TOTAL:					0
27881	TEMP CYCLE	-55C TO 125C		77	300	CYCL	0
		TOTAL:					0
27883	HAST, NO BIAS	130C, 85% R.H.		40	100	HOUR	0
		TOTAL:					0

PROJECT NO: 19205

RELIABILITY MONITOR

DS21S07 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	0047	DM035532AFD	20	TSSOP	4.4x0.9	Carsem

PROCESS 1P, 1M, 0.8um,Neg ZTC P1R,PdplD,Low Laser/Nit - Pass/Nit - General LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26588	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL: FAIL RATE (Fits):	14	DEVICE HRS: 6.76E+07		0
FAILURE MODE	**VERIFICATION**	**FA NUMBER**	**FAILURE MECHANISM**			
CONTINUITY						
26584	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26585	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85 C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
FAILURE MODE	**VERIFICATION**	**FA NUMBER**	**FAILURE MECHANISM**			
CONTINUITY	(#1,3,4)					
ACTIVE NEGAT	(#2)					
26586	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26589	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0

PROJECT NO: 17101

RELIABILITY MONITOR

DS21S07 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	0047	DM035532AFD	20	TSSOP	4.4x0.9	Carsem

PROCESS 1P, 1M, 0.8um,Neg ZTC P1R,PdplD,Low Laser/Nit - Pass/Nit - General LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26590	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
26591	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	36	96	HOUR	0
		TOTAL:				0

PROJECT NO: 17101

RELIABILITY MONITOR

DS2401 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	0130	DA033008AJ	3	TO92	150	Fastech

PROCESS 1P, 1M, 0.6um, Pd, Ti/TiN M1 , WJ Laser/TEOS Ox - Pass/Nit - Gen.LaserPrb

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27884	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		80	336	HOUR	0
		125C, 6.0 VOLTS		80	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.55E+07		0
27885	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
27886	HAST	130C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
27887	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

PROJECT NO: 19206

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 1M,0.6um,BCs,SilP1,Nd,PdD,Ti/TiN Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26508	INFANT LIFE	125C, 6.0 VOLTS		198	48	HOUR	0
26509	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		77	336	HOUR	0
		125C, 6.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	11	DEVICE HRS: 8.15E+07		0
26505	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26506	STORAGE LIFE	125C		203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.		203	144	HOUR	
	VAPOR PHASE REFLOW	220C		203	3	PASS	0
		TOTAL:					0
26507	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
26510	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
26511	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				41	959	HOUR	0

PROJECT NO: 16727

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 1M,0.6um,BCs,SilP1,Nd,PdD,Ti/TiN Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0

FAILURE MODE	VERIFICATION		FA NUMBER	FAILURE MECHANISM		
CONTINUITY						
26512	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16727

RELIABILITY MONITOR

DS5002 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0112	DN030363AAA	80	MQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 1M,0.6um,BCs,SilP1,Nd,PdD,Ti/TiN Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26901	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		77	336	HOUR	0
		125C, 6.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.14E+07		0
26898	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26899	STORAGE LIFE	125C		203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.		203	144	HOUR	
	VAPOR PHASE REFLOW	220C		203	3	PASS	0
		TOTAL:					0
26900	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
26902	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
26903	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				42	959	HOUR	0
		TOTAL:					0

PROJECT NO: 18041

RELIABILITY MONITOR

DS5002 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0112	DN030363AAA	80	MQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 1M,0.6um,BCs,SilP1,Nd,PdD,Ti/TiN Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C

Ea: 0.7 Vuse: 5.5 Volts

β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26904	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18041

RELIABILITY MONITOR

DS5002 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C6	0122	DN042297AAA	80	MQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 1M,0.6um,BCs,SilP1,Nd,PdD,Ti/TiN Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27364	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		80	336	HOUR	0
		125C, 6.0 VOLTS		80	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.55E+07		0
27361	ULTRASOUND	J-STD-020		4			
		TOTAL:					
27362	STORAGE LIFE	125C		206	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.		206	40	HOUR	
	CONVECTION REFLOW	220C		206	3	PASS	0
		TOTAL:					0
27363	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27365	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
27366	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				41	959	HOUR	0
		TOTAL:					0

PROJECT NO: 18779

RELIABILITY MONITOR

DS5002 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C6	0122	DN042297AAA	80	MQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 1M,0.6um,BCs,SilP1,Nd,PdD,Ti/TiN Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C

Ea: 0.7 Vuse: 5.5 Volts

β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27367	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18779

RELIABILITY MONITOR

DS80C320 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	0111	DH040746AA	40	PDIP	600	CPS (ChipPac, China

PROCESS 1P, 1M, 0.6um, SilP1, Pd, Ti/TiN M1 , N Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26894	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS		77	336	HOUR	0
		125C, 7.0 VOLTS		77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits):	13	DEVICE HRS: 7.26E+07		0
26895	TEMP CYCLE	-55C TO 125C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
26896	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
26897	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

PROJECT NO: 18021

RELIABILITY MONITOR

DS80CH11 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0103	DN029182AAA	128	LQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
26786	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		77	336	HOUR	0
		125C, 6.0 VOLTS		73	1000	HOUR	0
27058	INFANT LIFE	125C, 6.0 VOLTS		235	48	HOUR	0
		TOTAL:	FAIL RATE (Fits):	12	DEVICE HRS: 7.95E+07		0
26782	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
26783	STORAGE LIFE	125C		239	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.		239	240	HOUR	
	CONVECTION REFLOW	235C		239	3	PASS	
		TOTAL:					
26784	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
26787	TEMP CYCLE	-55C TO 125C		70	300	CYCL	0
				70	1000	CYCL	0
		TOTAL:					0
26788	BIASED MOISTURE	85/85, 5.5 VOLTS		48	274	HOUR	0
				45	959	HOUR	0

PROJECT NO: 17782

RELIABILITY MONITOR

DS80CH11 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0103	DN029182AAA	128	LQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
26789	HAST, NO BIAS	130C, 85% R.H.	40	100	HOUR	0
		TOTAL:				0

PROJECT NO: 17782

RELIABILITY MONITOR

DS80CH11 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0108	DN034351AA	128	LQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27107	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	2
		125C, 6.0 VOLTS	75	1000	HOUR	
		TOTAL: FAIL RATE (Fits):	131	DEVICE HRS: 2.38E+07		2
FAILURE MODE	**VERIFICATION**	**FA NUMBER**	**FAILURE MECHANISM**			
INTEL_STOP_M	STOP MODE					
27104	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27105	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	239	40	HOUR	
	CONVECTION REFLOW	235C	239	3	PASS	0
		TOTAL:				0
27106	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27108	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
		TOTAL:				0
27109	BIASED MOISTURE	85/85, 5.5 VOLTS	46	274	HOUR	1

PROJECT NO: 18662

RELIABILITY MONITOR

DS80CH11 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0108	DN034351AA	128	LQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				1

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
CONTINUITY	RESET TRIP		

27110	HAST, NO BIAS	130C, 85% R.H.	40	100	HOUR	1
		TOTAL:				1

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
INTEL_STOP_M	STOP MODE		

PROJECT NO: 18662

RELIABILITY MONITOR

DS80CH11 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0110	DC037148AA	128	LQFP	14x20x	Stats

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
27867	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS		80	336	HOUR	0
		125C, 6.0 VOLTS		80	1000	HOUR	
		TOTAL:	FAIL RATE (Fits):	36	DEVICE HRS: 2.54E+07		0
27864	ULTRASOUND	J-STD-020		4			0
		TOTAL:					0
27865	STORAGE LIFE	125C		242	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.		242	40	HOUR	
	CONVECTION REFLOW	235C		242	3	PASS	0
		TOTAL:					0
27866	PRECONDITION U/S	J-STD-020		4			0
		TOTAL:					0
27868	TEMP CYCLE	-55C TO 125C		70	300	CYCL	0
		TOTAL:					0
27869	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
		TOTAL:					0
27870	HAST, NO BIAS	130C, 85% R.H.		40	100	HOUR	0
		TOTAL:					0

PROJECT NO: 19203

RELIABILITY MONITOR

DS80CH11 SEP '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0110	DC037148AA	128	LQFP	14x20x	Stats

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	25 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	0		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS

PROJECT NO: 19203

RELIABILITY MONITOR

DS80CH11 DEC '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0113	DN036754AA	128	LQFP	14x20x	ATK (Amkor, K)

PROCESS 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+ Passivation w/Nov TEOS Oxide-Nitride

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 25 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 0

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
28601	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	80	336	HOUR	
		TOTAL: FAIL RATE (Fits): DEVICE HRS:				
28598	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
28599	STORAGE LIFE	125C	244	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	244	192	HOUR	
	CONVECTION REFLOW	235C	244	3	PASS	1
		TOTAL:				1

FAILURE MODE	VERIFICATION	FA NUMBER	FAILURE MECHANISM
HI_ADC_4K_RA	OFFSET		

28600	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0

PROJECT NO: 20887